

#### Product Change Notification / KSRA-17VISF459

#### Date:

21-May-2021

### **Product Category:**

Ethernet PHYs

#### PCN Type:

Manufacturing Change

#### **Notification Subject:**

CCB 4651 Final Notice: Qualification of STA as an additional assembly site for LAN8720A device family available in 24L VQFN (4x4x0.9mm) package

### **Affected CPNs:**

KSRA-17VISF459\_Affected\_CPN\_05212021.pdf KSRA-17VISF459\_Affected\_CPN\_05212021.csv

### **Notification Text:**

PCN Status: Final notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

**Description of Change:** Qualification of STA as an additional assembly site for LAN8720A device family available in 24L VQFN (4x4x0.9mm) package

#### Pre and Post Change Summary:

	Pre Change	Post Change		
Assembly Site	ASE Inc.	ASE Inc.	STATS Chippac Ltd.	
	(ASE)	(ASE)	(STA)	

Wire material	CuPd CuPd		CuPdAu		
Die attach material	EN-4900F	EN-4900F EN-4900F			
Molding compound material	G631B	G631B	G700E		
Lead frame material	C194	C194	C194		
	106 X 106 mils	106 X 106 mils	106 X 106 mils		
Lead frame paddle size	See attached pre and post change comparison				
DAP Surface Prep	Double Ring Plating	Double Ring Plating	Double Ring Plating		

#### Impacts to Data Sheet: None

Change Impact: None

Reason for Change: To improve manufacturability by qualifying STA as an additional assembly site

Change Implementation Status: In Progress

#### Estimated First Ship Date:

July 8, 2021 (date code: 2128)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

#### Time Table Summary:

	May 2021			>	July 2021						
Workweek	1 8	1 9	2 0	2 1	22		27	28	29	30	31
Qual Report Availability				x							
Final PCN Issue Date				х							
Estimated Implementation Date								x			

#### Method to Identify Change: Traceability code

Qualification Report: Please open the attachments included with this PCN labeled as PCN\_#\_Qual\_Report.

**Revision History: May 21, 2021:** Issued final notification. Attached the Qualification Report. Provided estimated first ship date to be on July 08, 2021.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

#### **Attachments:**

#### PCN\_KSRA-17VISF459\_Pre and Post Change Comparison.pdf PCN\_KSRA-17VISF459\_Qual\_Report.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

#### **Terms and Conditions:**

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our PCN home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the PCN FAQ section.

If you wish to <u>change your PCN profile, including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections. KSRA-17VISF459 - CCB 4651 Final Notice: Qualification of STA as an additional assembly site for LAN8720A device family available in 24L VQFN (4x4x0.9mm) package

Affected Catalog Part Numbers (CPN)

LAN8720A-CP LAN8720AI-CP LAN8720A-CP-TR LAN8720AI-CP-TR

# **CCB 4651**

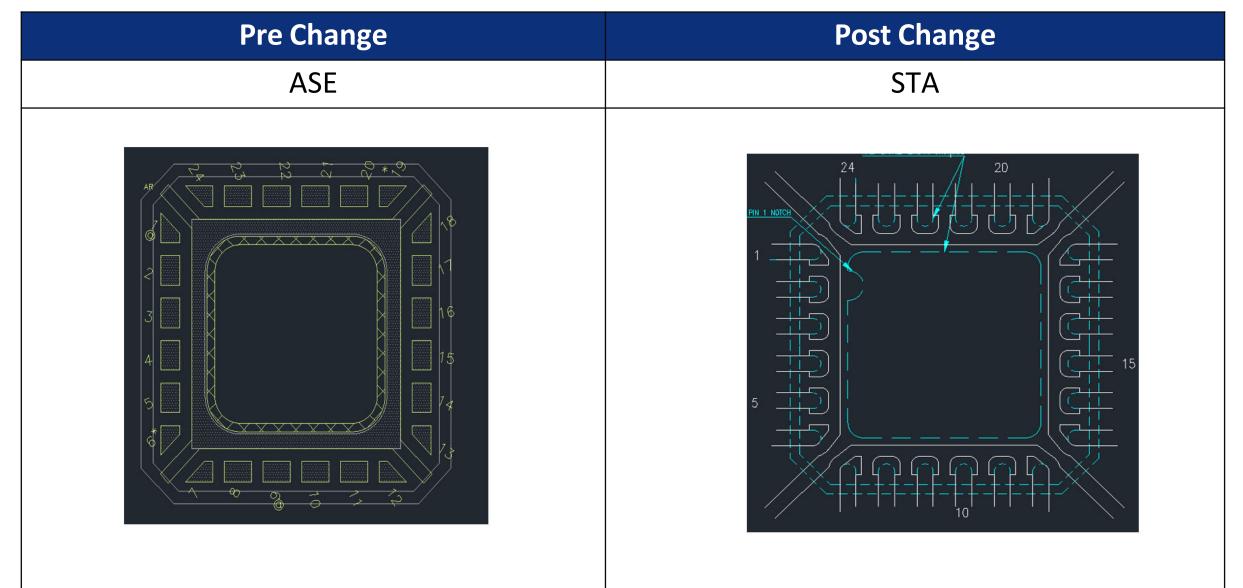
# Pre and Post Change Summary PCN # KSRA-17VISF459



A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



# Lead frame Comparison







## QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

# PCN #: KSRA-17VISF459

Date: May 21, 2021

Qualification of STA as an additional assembly site for selected products available in 32L VQFN (5x5x0.85 mm) package. The qualification of STA as additional assembly site for LAN8720A device family available in 24L VQFN (4x4x0.9mm) package will qualify by similarity (QBS). **Purpose:** Qualification of STA as an additional assembly site for selected products available in 32L VQFN (5x5x0.85 mm) package. The qualification of STA as additional assembly site for LAN8720A device family available in 24L VQFN (4x4x0.9mm) package will qualify by similarity (QBS).

	Assembly site	STA
	CCB No.	4651
Misc.	Qual ID	QAR2010-076
	Material	C194
Lead-Frame	Lead Plating	Ag (Ring plating) / Etched
	Leadframe Size	3.5 x 3.5 mm
BondWire	Material	CuPd
<u>DieAttach</u>	Part Number	8290
MC	Part Number	G700E
	PKG Type	VQFN
DKC	Pin/Ball Count	32
<u>PKG</u>	PKG width/size	5x5x0.85

#### **Assembly Process Data**

					<u> </u>
Process	Test Item	Criteria	Sample Size	Failure/	Remarks
1100033	rest tient	Onterna		Tested Qty.	Pass/Fail
Wafer Saw	Topside Chipping	50% max of damage	45 units/lot	0/45	Pass
	Backside Chipping	the guard ring	45 units/lot	0/45	Pass
	11 0	125µm max			
Die attach	Epoxy Void	10% max of die area	10 units/lot	0/10	Pass
	Bond Line	10-40µm	10 units/lot	0/10	Pass
Wirebond	Wirepull	3 gr. Min	20 wires/units	0/80	Pass
			4 units		
	Stitchpull	2.5 gr. Min	10 wires/units	0/50	Pass
		-	5 units		
	Ball Shear	8 gr min.	08 ball/units	0/40	Pass
		Ū.	5 units		
	Loop Height	250 µm Max.	10 wires/units	0/20	Pass
		•	2 units		
	Cratering	0 defects	03 unit/lot	0/3	Pass
	0		All pads		
	Au Intermetallic	60% min. Coverage	1 unit/lot	0/5	Pass
		g-	5 units		
Mold	Wiresweep	10% max of longest	10 units/lot	0/10	Pass
	•	wire			
Singulation	Package Dim	9+/-0.05mm	10 readings	0/10	Pass
Ŭ	5	9+/-0.05mm	10 readings	0/10	Pass
Plating	Thickness	10-18µm	20 readings	0/20	Pass
Thickness		'	5		

# SUMMARY RESULT OF RELIABILITY TEST

ITEM	CONDITION	BEFORE PRECONDITIONING O/S TEST SAT		AFTER PRECONDITIONING O/S TEST SAT	
PRECONDITIONING	30ºC / 60% RH 192 HRS, Level 3 per Jedec	0/240	0/240	0/240	0/240
TEST ITEM	TEST	TE	ST	VISUAL	O/S
(With Pre-Condition)	CONDITION	INTERVAL		Inspection	TEST
TEMPRATURE CYCLE TEST	JEDEC 22-A104 -65'C~150'C	1000/1500 CYC		0/60	0/60
HIGH TEMPERATURE STORAGE TEST	JEDEC 22-A103 150'C	1000/1500 HRS		0/60	0/60
HAST TEST (NO BIAS)	JEDEC 22-A118 130'C/85%RH 33.5PSIG	100/150 HRS		0/60	0/60
TEMPERATURE HUMIDITY TEST (NO BIAS)	JEDEC 22-A101 85'C/85%RH	1000/1500 HRS		0/60	0/60